

74AC/ACT11818

8-Bit Diagnostic/Pipe-Line Register

Objective Specification

FEATURES

- High-speed 8-bit parallel Output Register
- Serial diagnostic register with right-shift only
- Performs parallel-to-serial and serial to parallel conversion
- Output capability: ± 24 mA
- CMOS (AC) and TTL (ACT) voltage level inputs
- 50 Ω incident wave switching
- Center-pin V_{CC} and ground configuration to minimize high-speed switching noise
- I_{CC} category: MSI

DESCRIPTION

The 74AC/ACT11818 high-performance CMOS devices combine very high speed and high output drive comparable to the most advanced TTL families.

The 74AC/ACT11818 is a high-speed, general purpose pipeline register with an on-board diagnostic register for performing serial register diagnostics and write control store applications.

The D_n to Q_n path provides an 8-bit parallel data path pipeline register for normal system operation. The diagnostic register

GENERAL INFORMATION

SYMBOL	PARAMETER	CONDITIONS $T_A = 25^\circ\text{C}$; GND = 0V $V_{CC} = 5.0\text{V}$	TYPICAL		UNIT
			AC	ACT	
t_{PLH}/t_{PHL}	Propagation delay PCP to Q_n	$C_L = 50\text{pF}$	5.4	5.6	ns
C_{PD}	Power dissipation capacitance ¹	$f = 1\text{MHz}$; $C_L = 50\text{pF}$	Enabled: 17 Disabled: 6	17 6	pF
C_{IN}	Input capacitance	$V_I = 0\text{V}$ or V_{CC}	4.5	4.5	pF
C_{OUT}	Output capacitance	$V_O = 0\text{V}$ or V_{CC} ; Disabled	10	10	pF
C_{VO}	I/O capacitance	$V_{VO} = 0\text{V}$ or V_{CC} ; Disabled	12	12	pF
I_{LATCH}	Latch-up current	Per Jeduc Jc40.2 Standard 17	500	500	mA
f_{MAX}	Maximum clock frequency	$C_L = 50\text{pF}$; $V_{CC} = 5.5\text{V}$	100	100	MHz

Note:

1. C_{PD} is used to determine the dynamic power dissipation (P_D in μW):

$$P_D = C_{PD} \times V_{CC}^2 \times f_i + \sum (C_L \times V_{CC}^2 \times f_o) \text{ where:}$$

f_i = input frequency in MHz, C_L = output load capacitance in pF,

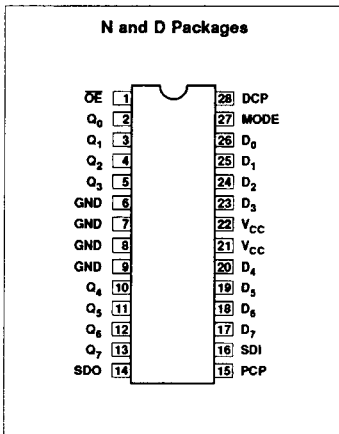
f_o = output frequency in MHz, V_{CC} = supply voltage in V,

$\sum (C_L \times V_{CC}^2 \times f_o)$ = sum of outputs

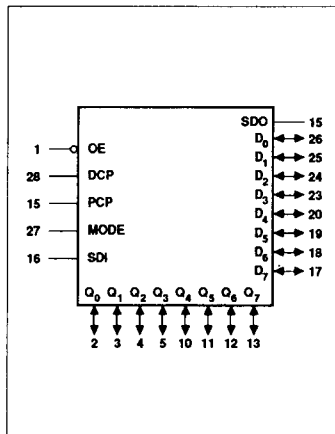
ORDERING INFORMATION

PACKAGES	TEMPERATURE RANGE	ORDER CODE
28-pin plastic DIP (300mil-wide)	-40°C to +85°C	74AC11818N 74ACT11818N
28-pin plastic SO (300mil-wide)	-40°C to +85°C	74AC11818D 74ACT11818D

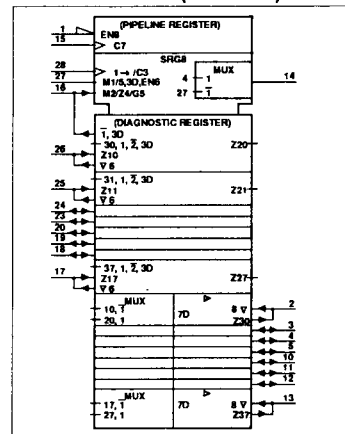
PIN CONFIGURATION



LOGIC SYMBOL



LOGIC SYMBOL (IEEE/IEC)



8-Bit Diagnostic/Pipe-Line Register

74AC/ACT11818

can load parallel data to or from the pipe-line register and can output data through the D_n I/O port.

The 8-bit diagnostic register has multiplexer inputs that select parallel inputs from the Q_n port or adjacent bits in the diagnostic register to operate as a right-

shift-only shift register. This register can then participate in a serial loop throughout the system where normal data, address, status, and control registers are replaced with the 74AC/ACT11818 Diagnostic Pipe-Line Registers. The loop can be used to scan in a complete test routine starting point (data, address, etc.). Then

after a specified number of clock cycles, the data clocked out can be compared to the expected results. Write control store loading can be accomplished using the same technique. An instruction word can be serially shifted into the diagnostic register and written into a write control store RAM by enabling the D_n outputs.

PIN DESCRIPTION

PIN NUMBER	SYMBOL	NAME AND FUNCTION
1	\overline{OE}	Output enable input (active Low)
28	DCP	Data (shadow register) clock
15	PCP	Pipe-line (output register) clock
27	MODE	Mode control input
16	SDI	Serial data control input
14	SDO	Serial data output
26, 25, 24, 23, 20, 19, 18, 17	$D_0 - D_7$	Data inputs/outputs
2, 3, 4, 5, 10, 11, 12, 13	$Q_0 - Q_7$	Data inputs/outputs
6, 7, 8, 9	GND	Ground (0V)
21, 22	V_{CC}	Positive supply voltage

FUNCTION TABLE

MODE	INPUTS				OUTPUT AND I/O			STATUS
	\overline{OE}	SDI	DCP	PCP	SDO	$Q_0 - Q_7$	$D_0 - D_7$	
L	X	X	↑	X	DR7*	—	Z	Serial input, shift right, disable $D_0 - D_7$
H	H	L	↑	X	SDI	INPUT	Z	Parallel load diagnostic register from $Q_0 - Q_7$, disable $D_0 - D_7$
H	L	L	↑	No ↑	SDI	OUTPUT	Z	Parallel load diagnostic register from pipeline register, disable $D_0 - D_7$
L	X	X	X	↑	DR7*	—	INPUT†	Load pipeline register from $D_0 - D_7$
L	X	X	↑	↑	DR7*	—	INPUT†	Load pipeline register from $D_0 - D_7$ while shifting diagnostic register
H	X	X	No ↑	↑	SDI	—	—	Load pipeline register from diagnostic register
H	X	X	X	X	SDI	—	—	Serial data in to serial data out
H	L	L	↑	↑	SDI	OUTPUT	Z	Exchange data between registers, $D_0 - D_7$ disabled
H	X	H	X	X	SDI	—	—	Hold diagnostic register, transitions on DCP do not effect diagnostic register
H	X	H	↑	X	SDI	—	OUTPUT	Enable $D_0 - D_7$ for parallel diagnostic register output

H = High voltage level

L = Low voltage level

↑ = Low-to-High clock transition

No ↑ = Don't allow Low-to-High clock transition

X = Don't care

Z = High-impedance state

* Internal node corresponding to the 8th bit of the Diagnostic Register

† The $D_0 - D_7$ outputs must be disabled before applying data to $D_0 - D_7$.

8-Bit Diagnostic/Pipe-Line Register

74AC/ACT11818

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	74AC11818			74ACT11818			UNIT
		Min	Nom	Max	Min	Nom	Max	
V_{CC}	DC supply voltage	3.0 ¹	5.0	5.5	4.5	5.0	5.5	V
V_I	Input voltage	0		V_{CC}	0		V_{CC}	V
V_O	Output voltage	0		V_{CC}	0		V_{CC}	V
$\Delta t/\Delta v$	Input transition rise or fall rate	0		10	0		10	ns/V
T_A	Operating free-air temperature	-40		+85	-40		+85	°C

NOTE:

1. No electrical or switching characteristics are specified at $V_{CC} < 3V$. Operation between 2V and 3V is not recommended, but within that range, a device output will maintain a previously established logic state.

ABSOLUTE MAXIMUM RATINGS¹

SYMBOL	PARAMETER	TEST CONDITIONS	RATING	UNIT
V_{CC}	DC supply voltage		-0.5 to +7.0	V
I_{IK} or V_I	DC input diode current ²	$V_I < 0$	-20	mA
		$V_I > V_{CC}$	20	
	DC input voltage		-0.5 to $V_{CC} + 0.5$	V
I_{OK} or V_O	DC output diode current ²	$V_O < 0$	-50	mA
		$V_O > V_{CC}$	50	
	DC output voltage		-0.5 to $V_{CC} + 0.5$	V
I_O	DC output source or sink current per output pin	$V_O = 0$ to V_{CC}	±50	mA
I_{CC} or I_{GND}	DC V_{CC} current		±225	mA
	DC ground current		±225	
T_{STG}	Storage temperature		-65 to 150	°C
P_{TOT}	Power dissipation per package Plastic DIP	Above 70°C: derate linearly by 8mW/K	500	mW
	Power dissipation per package Plastic surface mount (SO)	Above 70°C: derate linearly by 6mW/K	400	mW

NOTES:

- Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

8-Bit Diagnostic/Pipe-Line Register

74AC/ACT11818

DC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITIONS	74AC11818						74ACT11818			UNIT		
			$T_A = +25^\circ\text{C}$			$T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$			$T_A = +25^\circ\text{C}$		$T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$			
			Min	Typ	Max	Min	Typ	Max	Min	Max	Min		Max	
V_{IH}	High-level input voltage		V_{CC}	3.0	3.15	3.15	3.15	2.0	2.0	2.0		V		
				4.5	3.85	3.85	3.85	2.0	2.0	2.0				
				5.5	3.85	3.85	3.85	2.0	2.0	2.0				
V_{IL}	Low-level input voltage		V_{CC}	3.0	0.90	0.90	0.90					V		
				4.5	1.35	1.35	1.35	0.8	0.8	0.8				
				5.5	1.65	1.65	1.65	0.8	0.8	0.8				
V_{OH}	High-level output voltage	$V_I = V_{IL}$ or V_{IH}	$I_{OH} = -50\mu\text{A}$	V_{CC}	3.0	2.9	2.9	2.9				V		
					4.5	4.4	4.4	4.4	4.4	4.4	4.4			
					5.5	5.4	5.4	5.4	5.4	5.4	5.4			
				$I_{OH} = -4\text{mA}$	V_{CC}	3.0	2.58	2.48	2.48					
						4.5	3.94	3.8	3.8	3.94	3.8		3.8	
						5.5	4.94	4.8	4.8	4.94	4.8		4.8	
$I_{OH} = -75\text{mA}^1$	V_{CC}	5.5		3.85	3.85			3.85	3.85					
		5.5		3.85	3.85			3.85	3.85					
V_{OL}	Low-level output voltage	$V_I = V_{IL}$ or V_{IH}	$I_{OL} = 50\mu\text{A}$	V_{CC}	3.0	0.1	0.1	0.1				V		
					4.5	0.1	0.1	0.1	0.1	0.1	0.1			
					5.5	0.1	0.1	0.1	0.1	0.1	0.1			
				$I_{OL} = 12\text{mA}$	V_{CC}	3.0	0.36	0.44	0.44					
						4.5	0.36	0.44	0.44	0.36	0.44		0.44	
						5.5	0.36	0.44	0.44	0.36	0.44		0.44	
$I_{OL} = 75\text{mA}^1$	V_{CC}	5.5		1.65	1.65			1.65	1.65					
		5.5		1.65	1.65			1.65	1.65					
I_I	Input leakage current	$V_I = V_{CC}$ or GND	5.5	± 0.1	± 1.0	± 1.0	± 0.1	± 1.0	± 1.0	μA				
I_{OZ}	3-State output off-state current	$V_I = V_{IL}$ or V_{IH} , $V_O = V_{CC}$ or GND	5.5	± 0.5	± 5.0	± 5.0	± 0.5	± 5.0	± 5.0	μA				
I_{CC}	Quiescent supply current	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5	8.0	80	80	8.0	80	80	μA				
ΔI_{CC}	Supply current, TTL inputs High ²	One input at 3.4V, other inputs at V_{CC} or GND	5.5				0.9	1.0	1.0	mA				

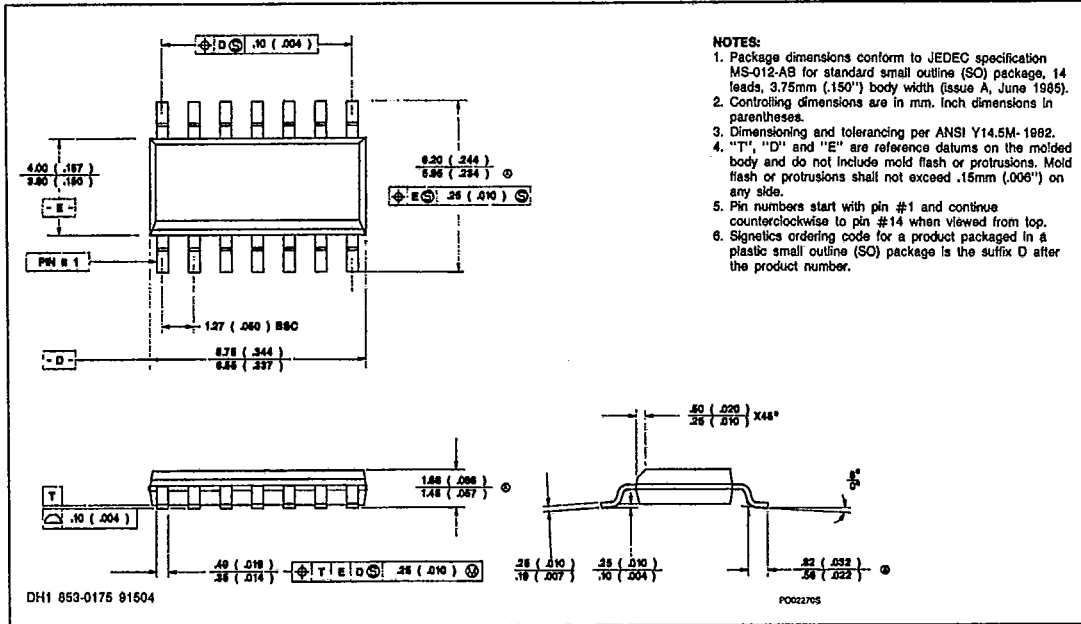
NOTES:

- Not more than one output should be tested at a time, and the duration of the test should not exceed 10ms.
- This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0V or V_{CC} .

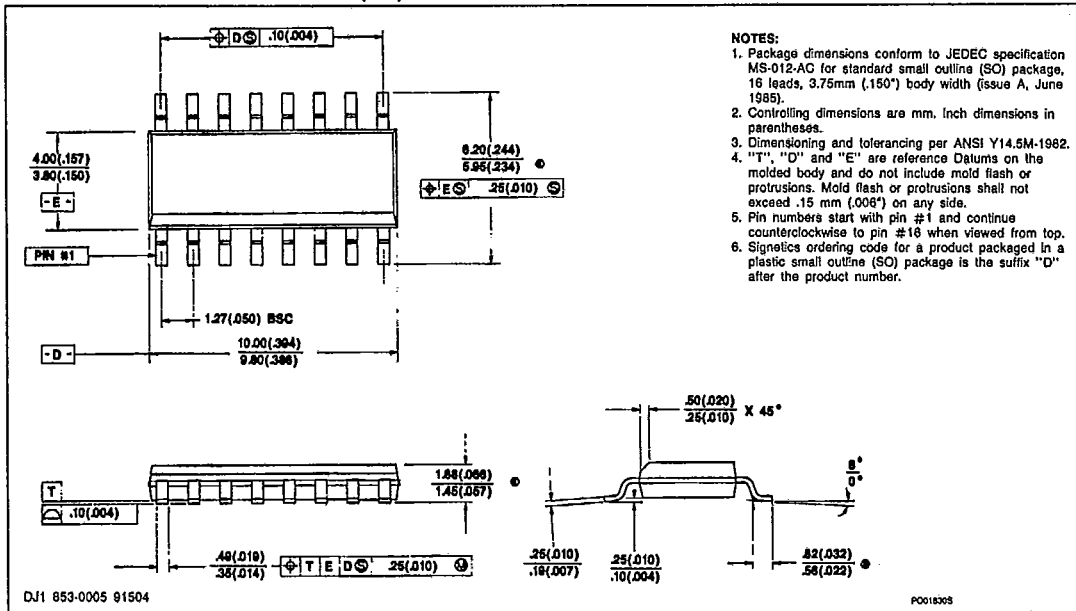
Packaging Information

T-90-20

14-PIN PLASTIC SMALL OUTLINE (SO)

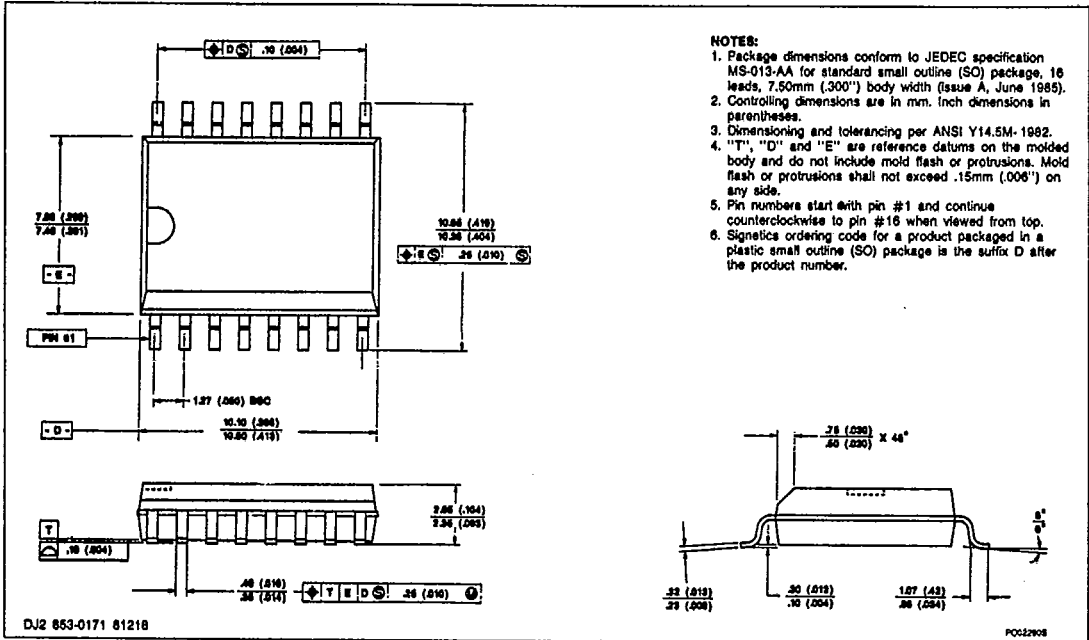


16-PIN PLASTIC SMALL OUTLINE (SO)

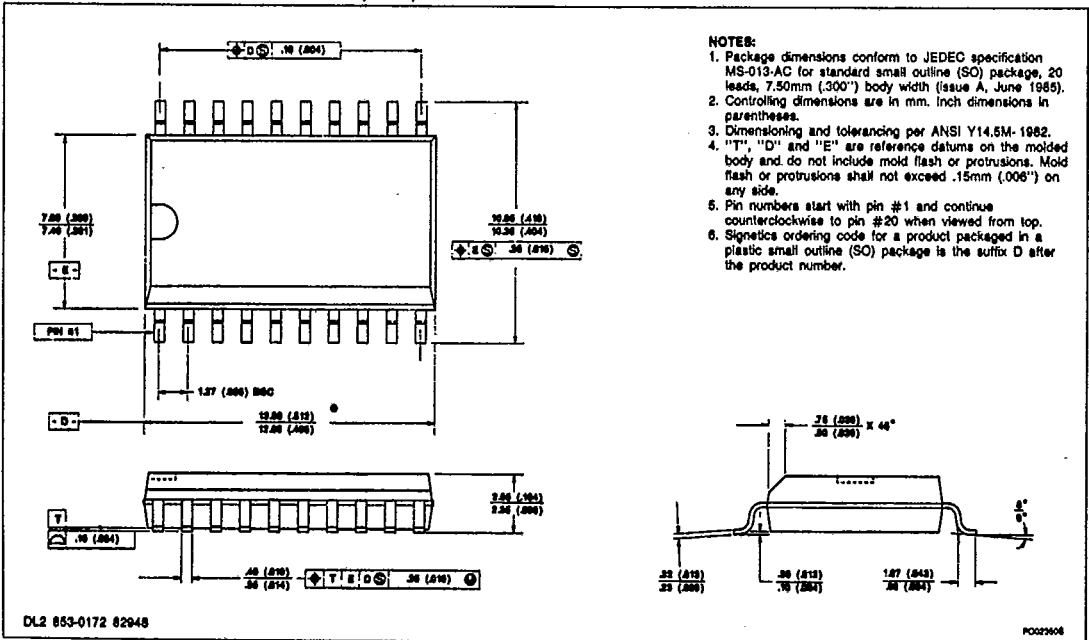


Packaging Information

16-PIN PLASTIC SMALL OUTLINE (SOL)

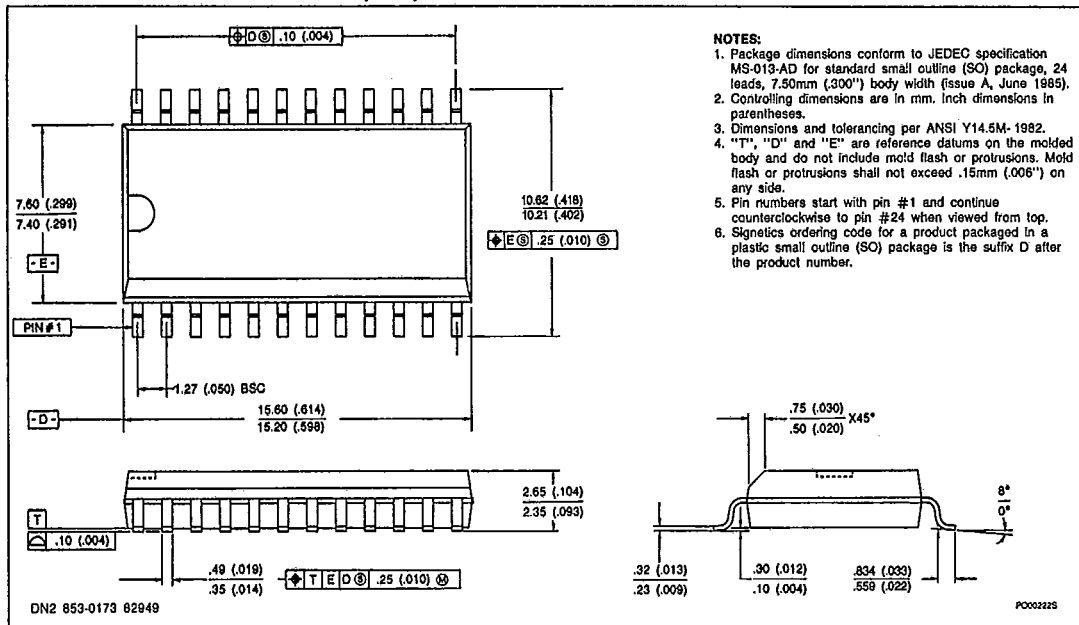


20-PIN PLASTIC SMALL OUTLINE (SOL)

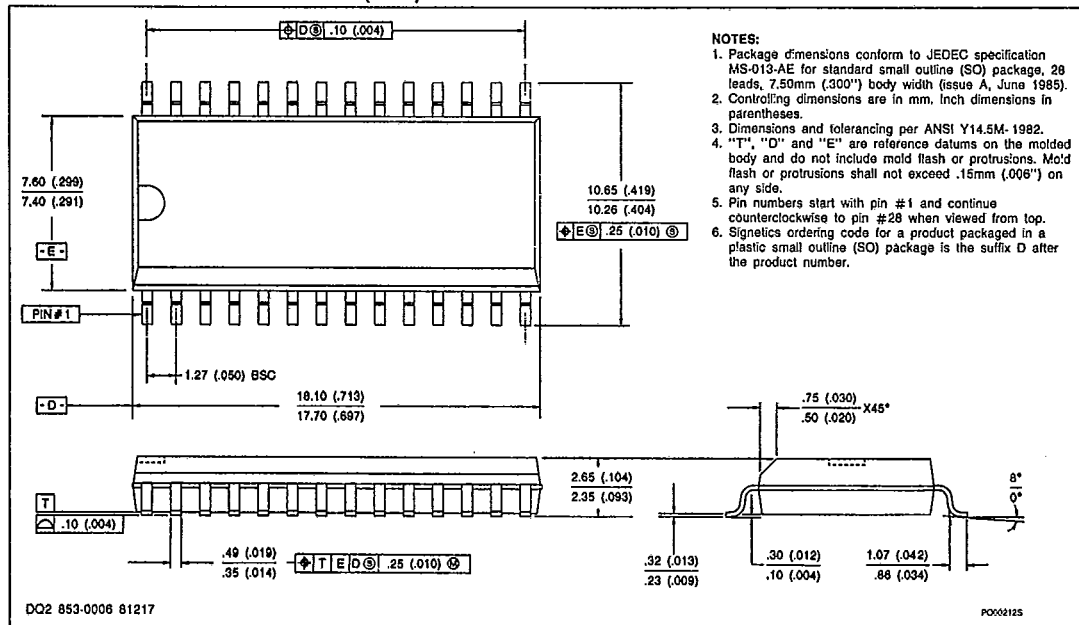


Packaging Information

24-PIN PLASTIC SMALL OUTLINE (SOL)



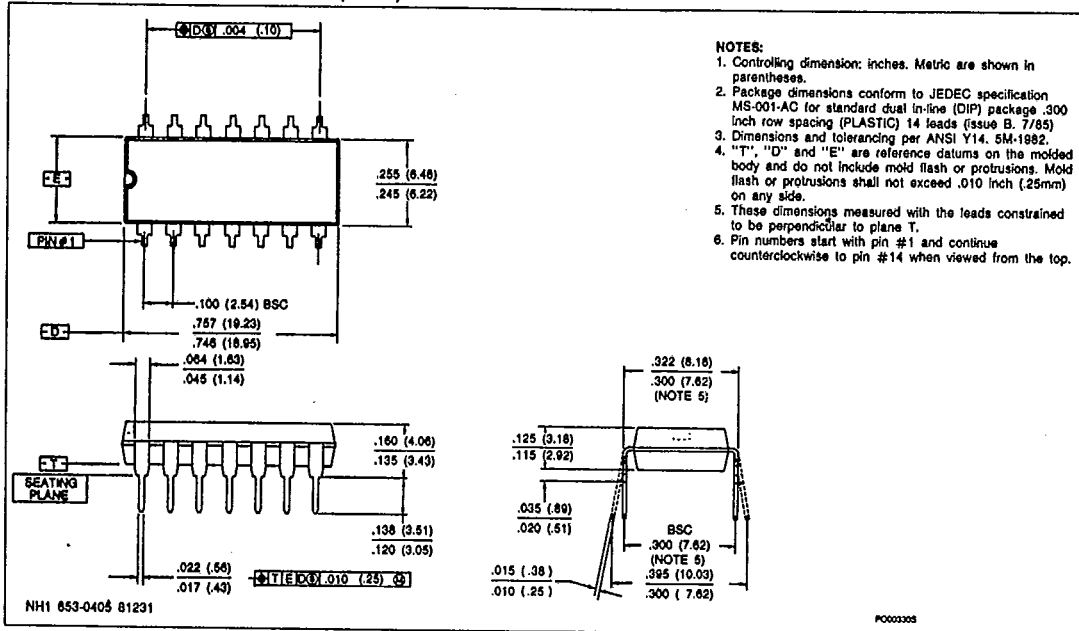
28-PIN PLASTIC SMALL OUTLINE (SOL)



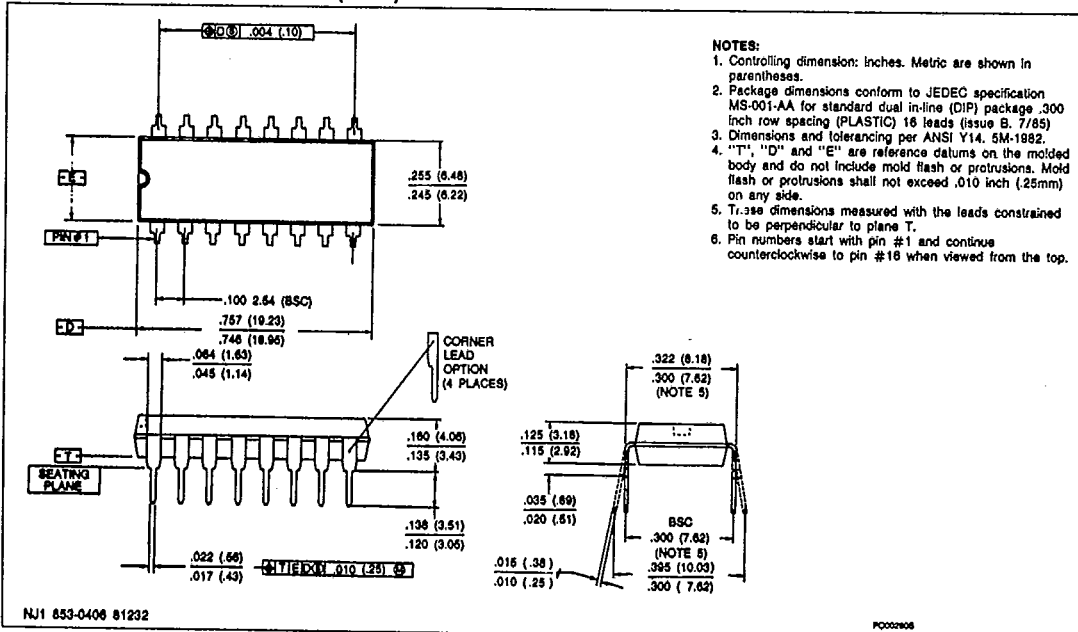
Packaging Information

T-90-20

14-PIN PLASTIC DUAL IN-LINE (PDIP)



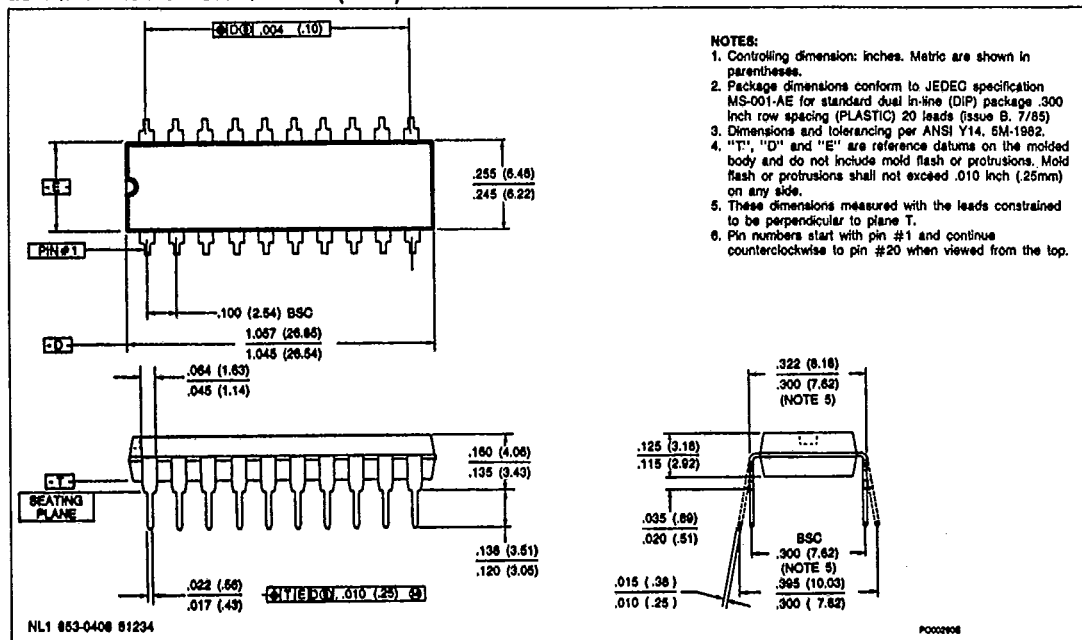
16-PIN PLASTIC DUAL IN-LINE (PDIP)



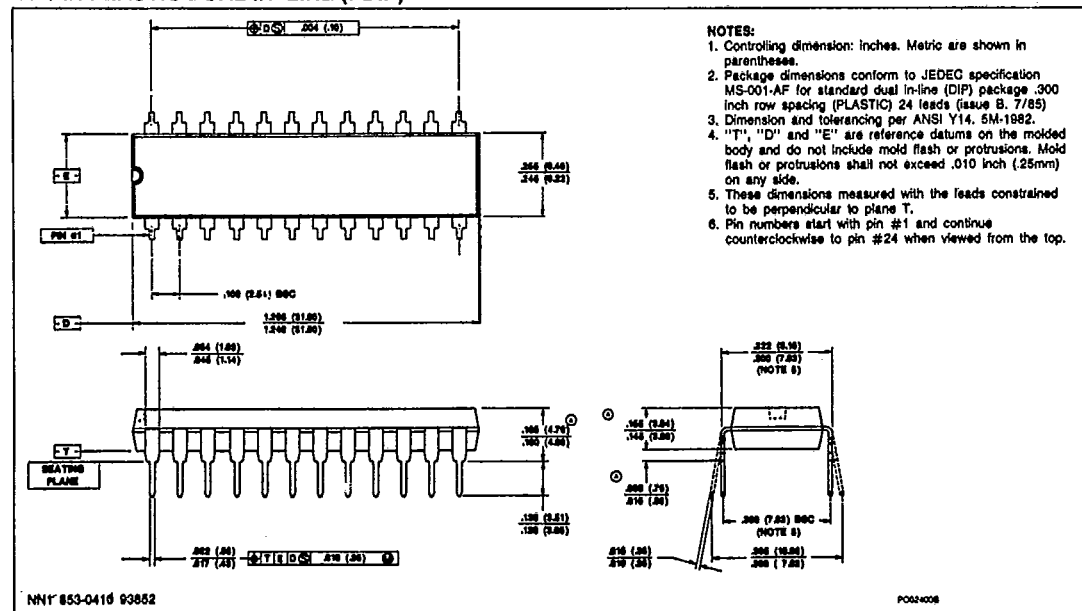
Packaging Information

T-90-20

20-PIN PLASTIC DUAL IN-LINE (PDIP)



24-PIN PLASTIC DUAL IN-LINE (PDIP)



Packaging Information

28-PIN PLASTIC DUAL IN-LINE (PDIP) (300-mil-wide)

